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Surface defects in water vapour barrier layers for structured plastic electronics

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Topical Meeting: Structured and Freeform Surfaces
NPL Teddington, UK
December 2012

The paper presents results from the first stages of NanoMend
NanoMend
European Framework 7 Programme
NMP-2011 Nanoscale, Nanotechnologies, Materials and New Production Technologies.
£7.2 million, 4 year long project
14 European Partners

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- The Project
- Project Ambition
- Applications
- Flexible PV
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Consortia

Applications
NanoMend will tailor its technology to the specific needs of the following applications:

Flexible solar modules
The food packaging

Project Ambition
To develop technologies that are able to detect and correct micro and nano-scale defects in Roll to Roll produced films, without slowing production speed.

In order to improve product performance, yield and lifetime.

Flexible solar modules
The food packaging
**Why is this project necessary**

- Thin films can take the form of:
  - Functional layers within a product (flexible photovoltaics).
  - Protective coatings (used to weatherproof flexible photovoltaics, food packaging, digital displays, other applications).

**NanoMend Flexible Solar Modules; basic layer groupings**

**Functional elements of flexible photovoltaic cells**

- Encapsulation of the PV layer by polymer film layers is designed to protect the PV modules from water ingress through the polymer layers to the cells which reduces efficiency over time.
- The most expensive element of PV cells per m² is the barrier layer.
- ALD layer of Al₂O₃ 40nm thick on a planarised polymer substrate.
Encapsulation 2

- Defects: “pin holes” and particles in the ALD layer are thought to significantly affect the barrier properties.
- Test substrates were produced at CPI and measured using a MOCON Water Vapour Transmission Rate (WVTR) test.

Defects density and its correlation with WVTR

- Water vapor transmission rate (WVTR) for 40nm film at specified conditions: 38°C @90% RH.

<table>
<thead>
<tr>
<th>Sample</th>
<th>WVTR (g/m²/24 hr)</th>
</tr>
</thead>
<tbody>
<tr>
<td>Sample 2701</td>
<td>1.1 x 10⁻³</td>
</tr>
<tr>
<td>Sample 2702</td>
<td>1.3 x 10⁻³</td>
</tr>
<tr>
<td>Sample 2705</td>
<td>4.1 x 10⁻³</td>
</tr>
<tr>
<td>Sample 2706</td>
<td>2.0 x 10⁻³</td>
</tr>
</tbody>
</table>

- From the above table it can be observed that sample 2705 has the highest value of WVTR.

Visualisation of defects

Scale of large defects

Scale of small defects

Optical microscope images × 2000× magnification

Types of defects 1

- Pinholes
- Ranging from 1 to 3μm in size

Types of defects 2

- Peaks/particles of ≤ 30 nm height

Types of defects

- Holes
- Of about 60 μm lateral dimension
Defining significant peaks and dales

- Density of peaks: \( \frac{S_d}{mm^2} \)
- Density of dales (pits): \( \frac{S_d}{mm^2} \)
- Density of significant defects: \( \frac{S_d}{mm^2} \)

When counting all defects there was no correlation between WVTR and possible defect density or types.

\[ \text{Possible defect counters} \]

Density of dales, \( S_{dd} \)

- A dales is defined as a region around a pit such that all maximal downward paths end at the pit (ISO 29178-22012(B)).

Exercise 1

Exercise 2

Exercise 3

Structured Feature ‘Filtering’ - Wolf Pruning

- Noise and measurement errors can also create artificial “small” critical points.
- Function splits features into functionally significant and insignificant sets.

Exercise 4

“Number of data files with large defects”

- Exercise 4: A comparison of defects on sample 2705 and sample 2706.
- More than 500 locations were inspected at a magnification of X 20 on the CCD for both samples.
- Only large defects (for \( D > 0.1 \mu m \)) were considered.
- Small numbers of larger defects seem to have the dominant effect on WVTR (no clear distinction between peaks and dales)

Super-resolution

- Clearly many defects are smaller than the diffraction limit any may affect WVTR.
- A priori data can be used with super-resolution techniques to measure (or simply detect) sub-resolution features.
- NPL developing instrumentation along with phase-retrieval techniques.
- Investigating the use of optical singularities.
Structured Surface Analysis in Flexible PV metrology

Laser Cell scribing in Mo back contact
Optical & CCI analysis
- The PV cell back contact is made from a layer of Molybdenum. After the coated polymer web leaves the vacuum chamber, it passes over a laser that scribes lines into the metallic layer to delineate the individual solar cell back-contact.

Laser Cell scribing in Mo back contact
- Defects “bridging” the cell gaps can give rise to shorts across cell reducing overall efficiency.

Interferometer analysis of defect
- Particle inside the scribe line.
- Height 1 um.
- Width about 16um
- EDAX analysis confirms Mo

Step Height Segmentation across defect area
- Set trough bottom to be zero and use
  - Relative heights
  - Through width
  - Defect width as % of through width
- As a defect detector

Light Management Film Dimensions
- Insert picture microsharp
Original surface structure
A roll to roll, UV casting process that produces microstructure to extreme accuracy is implemented.

Defective in optical film (AFM)
Defect size scale
Width 0.57um
Depth 60um

In Process Systems Wavelength scanning Interferometry (WSI)

Conclusions
- Flexible PV cells critical functionality depends on barrier properties
- Defect density seems to correlate with WVTR
- Structured surface approach useful in monitoring defect presence in all layers
- In process sensors needed!

Acknowledgements
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